

Features

- Frequency: 0.7~5GHz
- Gain: 21dB
- OutputP₋₁dB: 16dBm
- Supply Voltage: +5V@120mA
- Die Size: 2.5mm×2.1mm×0.1mm

Typical Applications

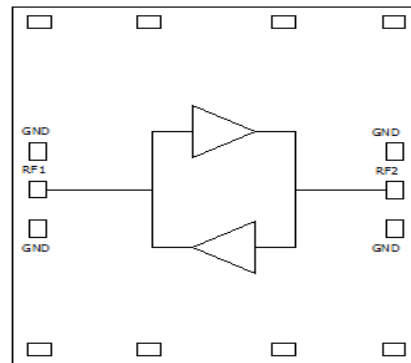
- EW
- Military Radar and Weather Radar
- SATCOM
- Beamforming
- Phase Shift

General Description

SAC3609 is a bi-directional MMIC amplifier which operates between 0.7GHz to 5GHz. It is fabricated using GaAs process. It has bi-directional amplification function, and can be switched between forward/reverse amplification by external digital control signal. It provides 21dB gain and 16dBm OutputP₋₁dB by consuming 120mA current.

The chip is back-metalized to ensure better grounding. It can be die-mounted with AuSn eutectic preform or with electrically conductive epoxy.

Functional Diagram



Electrical Performance (T_A=25°C, V_D=+5V, I_D=120mA, Z₀=50Ω)

Parameter	Min.	Typ.	Max.	Units
Frequency	0.7~5			GHz
Gain	—	21	—	dB
Gain Flatness	—	1	—	dB
Reserve Isolation	—	-37	—	dB
Input VSWR/ Output VSWR	—	1.5	—	: 1
Noise Figure	—	4.5	—	dB
OutputP ₋₁ dB	—	16	—	dBm
OutputIP ₃	—	26	—	dBm
Supply Current(I _D)	—	120	—	mA

Absolute Maximum Ratings

RF Input Power	18dBm	Control Voltage Range	-5.5~+0.5V
Channel temperature	150°C	Storage Temperature	-65°C~+150°C
Operating Temperature	-55°C~+85°C	ESD protection level (HBM)	Class 1A

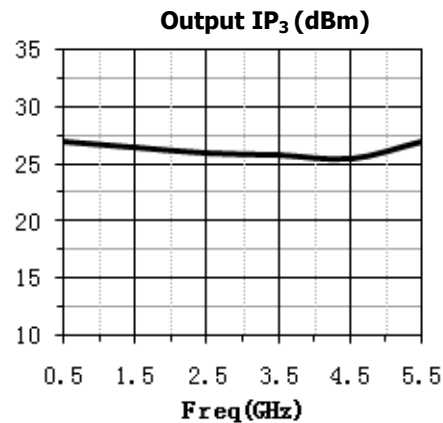
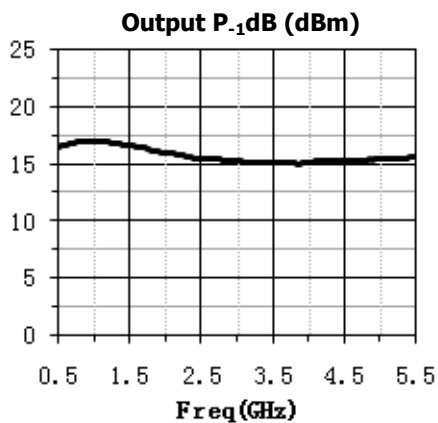
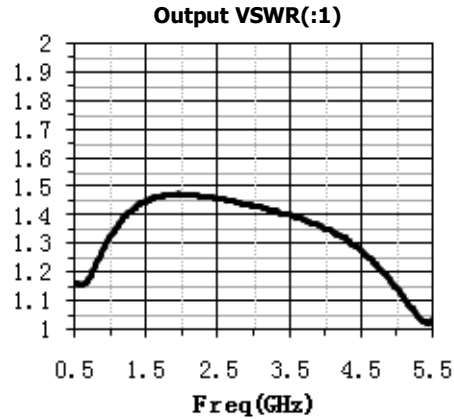
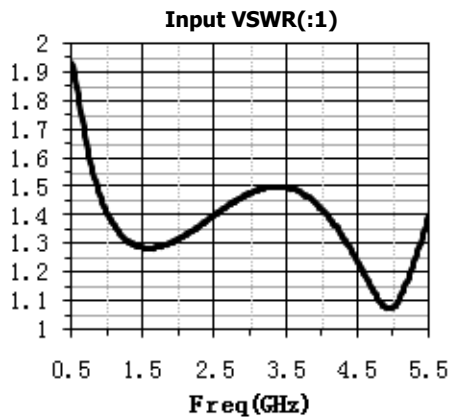
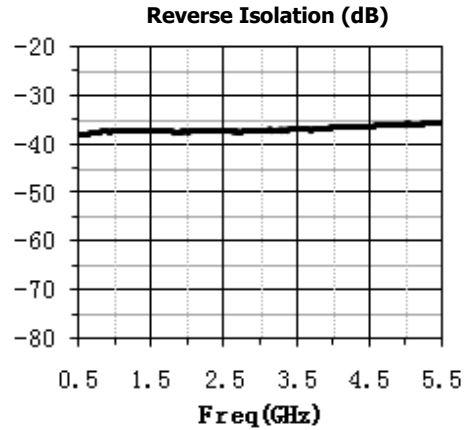
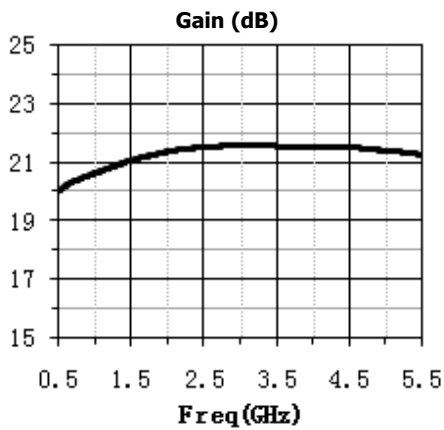
Truth Table

State		Amplification State
Vc	Low	RFC1-RF2 ON
	High	RFC2-RF1 ON

Control Voltage

State	Bias Condition
Low	0~ 0.2V
High	3~ +5V

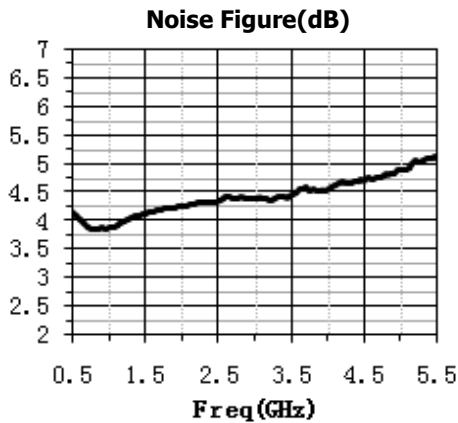
Typical Performance Curve



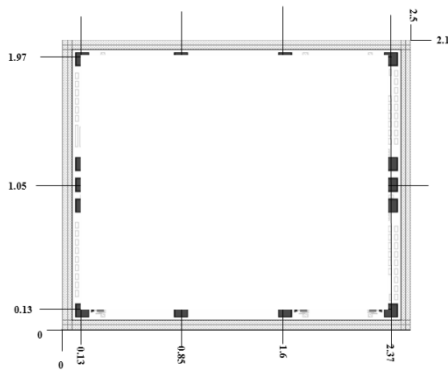
SAC3609

GaAs Bi-directional Amplifier
0.7GHz~5GHz

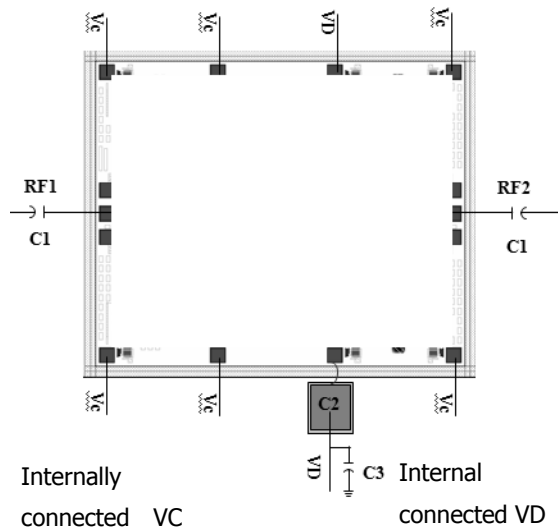
Rev 2.1



Die Outline
(all dimensions in mm)



Assembly Diagram



Components List

Reference Des.	Value	Part Number	Manuf.	Size
C1	100pF	GRM155C1H101JZ01D	MURATA	0402
C2	100pF	-	RADVISTA	Chip
C3	10nF	GRM155R71H103KA88D	MURATA	0402

Attention:

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.